

No.	Code	Title – Instrumentation and Development	Author
1	OI0101	Probing Structure and Electronic Structure of Battery Materials at Atomic Scale by Scanning Transmission Electron Microscopy	Lin Gu
2	OI0102	3D Fourier transform analysis to evaluate a high-performance TEM	Kazuo Ishizuka and Koji Kimoto
3	OI0103	Quantitative Experimental Determination of Site-specific Magnetic Structures by Transmitted Electrons	Xiaoyan Zhong, Ziqiang Wang, Rong Yu, Jing Zhu
4	OI0301	Electron Diffraction Analysis of Microcrystalline of Organic Molecules	Tetsuo Oikawa, Anna Liew, Yusuke Nishiyama
5	OI0302	Quantification of crystallinity using energy filtered electron diffraction	Byeong-Seon An, Tae-Hoon Kim, Cheol-Woong Yang
6	OI0303	A Relativistic-energy Femtosecond-pulse Electron Microscopy	Jinfeng Yang, Yoichi Yoshida, Katsumi Tanimura
7	OI0304	MEMS Waveguide Sensor for Photoacoustic Detection	Supanee Larkthanakhachon, Suejit Pechprasarn, Mike Somekh
8	OI0501	In situ TEM Study of Vapor-Solid Nanotube Growth	Zhengfei Zhang, Yong Wang, Hengbo Li, Wentao Yuan, Ze Zhang
9	OI0502	<i>In situ</i> electron holography of electric potentials inside a solid-state electrolyte: Effect of 3D electric-field leakage	Tsukasa Hirayama, Yuka Aizawa, Kazuo Yamamoto, Takeshi Sato, Hidekazu Murata, Ryuji Yoshida, Craig A. J. Fisher, Takehisa Kato, Yasutoshi Iriyama
10	OI0503	Improved heating stage for EBSD In-Situ work	Seiichi SUZUKI, Tatsuya FUKINO
11	OI0504	In-situ TEM study of nano-scale conductive filament used for threshold selector device	Byeong Gyu Chae, Kyung Joon Baek, Jeong Hwan Song, Jae Bok Seol, Hyun Sang Hwang, Sang Ho Oh, Chan Gyung Park
12	OI0505	In-situ TEM study of deformation behavior in a dual-phase high-entropy alloy AlCoCrFeNi	Qiannan Wang, Qian Yu
13	OI0506	In-situ Nanoengineering Based on TEM	Tao Xu, Hengchang Bi, Shu Wan, Jun Sun, Longbing He, Kuibo Yin, Litao Sun
14	OI0507	Ultra-High Resolution SEM for 3D Analysis in Biology	Jaroslav Jiruse, Miloslav Havelka, Jan Polster
15	OI0601	Study of Pseudo-Symmetric Misindexing in EBSD Analysis of $\gamma$ -TiAl Alloys with Refined Accuracy Band Detection	Wu Jiang, Niels-Henrik Schmidt, Alberto Palomares-García, Rocío Muñoz-Moreno, and Jenny Goulden
16	OI0602	Direct Observation of low angle boundary migration during recrystallization using Electron Channeling Contrast Imaging and Electron Backscatter Diffraction	Jin-Su Oh, Seung-Moon Baek, Tae-Hoon Kim, Jee-Hwan Bae, and Cheol-Woong Yang
17	OI0701	Ultra-sensitive biosensor using double-metallic-layer-waveguide structure	Mengqi Shen, Jingkai Meng, Supanee Larkthanakhachon, Suejit Pechprasarn, Michael G. Somekh, Yaping Zhang, Chung W. See
18	OI0702	Embedded interferometry with dynamic reference beam	Wai-Kin Chow, Suejit Pechprasarn, Michael G. Somekh
19	OI0901	Improvement of mass resolution in atom probe tomography for oxide materials with surface modification	Chang Min Kwak, Jae Bok Seol, Chan Gyung Park

20	OI1001	Quality enhancement and strain measurement in HAADF images using Super-Resolution techniques	G. Bárcena-González, M. P. Guerrero-Lebrero, E. Guerrero, D. F. Reyes, D. González, A. Mayoral, A. D. Utrilla, J. M. Ulloa, P. L. Galindo
21	OI1101	Digital transformation in Microscopy Teaching	Silvia Zenner-Gellrich, Peter Kraemer
22	OI1301	Effects of Nickel Oxide Underlayer on the Catalytic Properties of Manganese Oxide Nanoparticles	Sangmoon Yoon, Kyoungsuk Jin, Won Woo Chung, Ki Tae Nam and Miyoung Kim
	PI01	Study of low voltage contrast imaging of graphene by the linkage with SEM and SPM	Shuichi Takeuchi, Yoichiro Hashimoto, Kazunori Ando, Takeshi Sunaoshi, Atsushi Miyaki, Masahiro Sasajima, Takehiro Yamaoka
	PI02	A Sample Extend Abstract Title Design and Application of In-situ TEM Holder with Electrochemical Function at Operating Condition	Mu Tung Chang, Shen-Chuan Lo, C.Y.Hsieh, Sung-Yen Wei, Ren-Fong Cai
	PI03	First results of prototype EELS system for low voltage cold FE-SEM	Satoshi Okada, Yu Yamazawa, Zulihuma Yasenjiang, Takeshi Sunaoshi, Kazutoshi Kaji
	PI04	Quantitative Microanalysis at Low Voltage With a WDS Electron Microscope Equipped With a FE Column	Pierre-Yves Corre, Chrystel Hombourger and Michel Outrequin
	PI05	Scanning transmission electron microscope –transition edge sensor (STEM-TES)	Keiichi Tanaka, Toru Hara, Kazuhisa Mitsuda, Keisuke Maehata
	PI06	Valance and coordination mapping using monochromated STEM EELS	He Tian
	PI07	Measurement of fogging electron current in scanning electron microscope	Yoshifumi Hagiwara, Taku Noda, Masatoshi Kotera, Raynald Gauvin
	PI08	Technical development of cryo-SEM workflow for direct observation of a hydrated emulsion adhesive.	Yuri Nishino, Ayumi Ishihara, Yoshiko Ito, Atsuo Miyazawa
	PI09	Development of trajectory simulation of fogging electrons in a vacuum specimen chamber	Kazumasa Terada, Taiki Nishino, Taku Noda and Masatoshi Kotera
	PI10	Structure retrieval using segmented detectors in scanning transmission electron microscopy	H. G. Brown, A. J. D'Alfonso, Z. Chen, A. J. Morgan, M. Weyland, C. Zheng, M. S. Fuhrer, S. D. Findlay and L. J. Allen
	PI11	Single-shot Electron Diffraction using Relativistic-energy Femtosecond Electron Pulse	Ryo Asakawa, Jinfeng Yang, Takafumi Kondoh, Koichi Kan, Masao Gohdo, Yoichi Yoshida, Katsumi Tanimura
	PI12	An history of EBSD- a one thousand factor!	Francois Brisset
	PI13	Application of non-tiling extra-large field observation and analysis using SEM	Yuji Hasebe, Seiichi Suzuki, Shunsuke Asahina, Takeshi Nokuo
	PI14	Grating Structured Light Illumination Microscopy	Alexandr Melnikov, Michael G. Somekh
	PI15	Dependence of the working distance and the applied bias on the surface potential distribution of insulating specimen irradiated by electron beam	Takuya Kawamoto, Masashi Tokai, Masatoshi Kotera
	PI16	A Handy Method for High Quality Specimen Preparation for Chip-based in-	Ya Wang, Jun Liu, Lu Chen, Yong Wang

		situ Transmission Electron Microscopy	
	PI17	Low Energy X-ray Analysis for Light Element and High Spatial Resolution SEM-EDS	James Sagar, Wu Jiang, James Holland, Simon Burgess
	PI18	Optimization of the FIB induced damage in TEM diamond samples	Sergey Rubanov
	PI19	Scanning Confocal Microscope Using Digital Micromirror Device (DMD)	Sani Boonyagul, Kodchakorn Ittipornnuson and Suejit Pechprasarn